## Search Notes



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10717607	KIM ET AL.	
Examiner	Art Unit	
Keefer, Michael E	2154	

SEARCHED						
Class		Subclass	Date	Examiner		
709	227		7/13/2007	MEK		

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST Search	7/13/2007	MEK		
Consulted Examiner Hassan Phillips	7/12/2007	MEK		
Consulted Examiner Dustin Nguyen	7/12/2007	MEK		

INTERFERENCE SEARCH				
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